

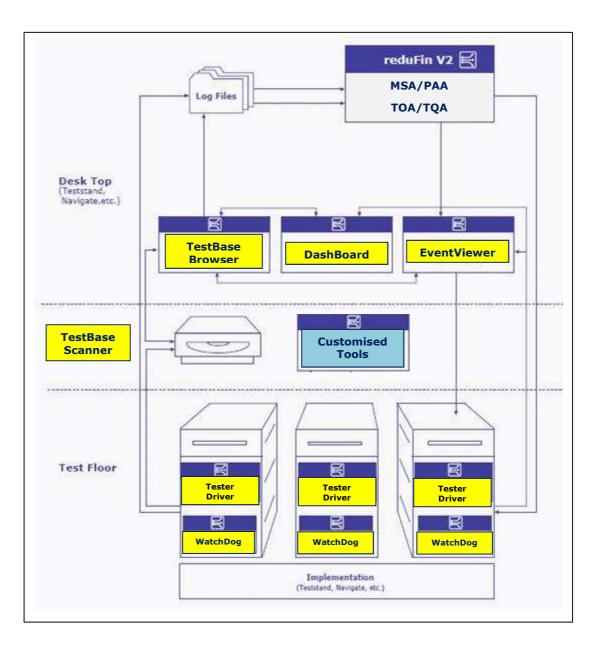
The optimiSE Test Management Suite

Our **Test Management Suite** offers a unique combination of automated ("real-time") production control, desk-top analysis as well as customised tools. All of them are specially designed for the development, analysis and optimisation of test programs and test hardware

- The **Test Management Suite** replies to most questions concerning test floor activities and, in doing so, it delivers multiple benefits for the Test Program Development, Test Engineering and Quality Management
- A Data Base tailored to Test Engineering Needs the TestBase The TestBase's automated data collection scans all device characteristics and test results into a data base (PostGreSQL or standard company DB, e.g., MSSQL/Oracle/IBM). The TestBase Browser provides full device and test data traceability for actual or long-term analyses.
- A smart Production Control Unit the Tester DashBoard The DashBoard permits the production/quality/test executives to view actual information concerning the product quality (First Pass Yield, # of Retests) as well as the usage of test machines, with all information in realtime or for long-term analyses. It also serves as an automated product and tester controller with threshold violation warnings in real-time (e.g. First Pass Yield). Moreover, it helps optimising the tester usage as handling times, 'left-over' tester capacities, etc. are indicated.
- An all-in-one Tool for Test Analysis the reduFin Suite reduFin is able to analyse data logs in any format or load data from the TestBase. With its four <u>mutually independent</u> modules, reduFin transforms test data into most detailed knowledge and reporting about
 - GR&R (all tests in one run!)
 - Part Average Analysis
 - Test Program and Hardware Qualification
 - Test Time Reduction for Inline Test

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The TMS Scheme

Yellow = > Automated tools operating mainly in background

The following pages provide a more detailed look at our product range!

Need more information? Please see www.optimise.de

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The **TestBase**

- Automatic test report logging with the Windows Service TestBase
 Scanner any standard or proprietary format is accepted.
- Data pool for part traceability and test analysis by the **DashBoard** and **reduFin**.
- To be used as "desktop" DB on PostGreSQL-frame or embedded into the local company DB structure (MS, IBM, Oracle, etc.)
- Test-Pareto Analyses are executed directly in the Browser. For ,indepth' analyses reduFin can be started and loaded with the corresponding data from the Browser.
- **TestBase** combines the advantages of a standardised database (e.g. MS SQL Server Management) with an optimised database design, which has been configured for highest efficiency in the display of PC Band test properties

-									Bro	wser (SQL2008) - optimiSE Test	Base Solution					0	
0	atabase	Extras															PCB E	dition
Query 00 Query 1	Se	Filter up-to-date earch		ې د Load S Filter		Filter Test De on/off on/ol	tails Pe		tatistics QA Re on/off on/o	port reduF	n TQA E	xport Data III Export						
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					•			PULSP3-DH		Pass			. 2013-01-02 05:51		TM_PULSP		2. Fail 113520	
ice Status				-	_	2 NODIF		PULSP3-DH		Pass	PF-FKT-RMT1		. 2013-01-02 05:55	REICHH	TM_PULSP		3. Interrupted 46062 2. First Pass Yield of PCB's	
rt Time		2012	-08-06 00:00	-				PULSP3-DH		Pass			. 2013-01-02 05:57		TM_PULSP		FP Yield 96.73 %	
o Time	T	oday	-02-03 00:00					PULSP3-DH		Pass			. 2013-01-02 06:00	REICHH	TM_PULSP		3. Retests	
5 11110		2010	02 00 00.00					PULSP3-DH		Pass			2013-01-02 06:02		TM_PULSP		Retest Time 3383.08:45:5	8
t System				-		6 NODIF	RECT	PULSP3-DH	23912611	Pass	PF-FKT-RMT1	2013-01-02 06:05	. 2013-01-02 06:05	REICHH	TM_PULSP	1	Retest-Zähler 1113900	
: System Sf	5N			-		7 NODIF	RECT	PULSP3-DH	23912852	Interrupted	PF-FKT-RM	2013-01-02 06:06	. 2013-01-02 06:06	REICHH	TM_PULSP	1	Tester Retest Tin: 451.04:33:46 Tester Retests 257959	
rator				-		8 NODIF	RECT	PULSP3-DH	23912936	Pass	PF-FKT-RMT1	2013-01-02 06:10	2013-01-02.06:10	REICHH	TM_PULSP	1	4. Deficiencies	
ogram Nam	ne			-		9 NODIF	RECT	PULSP3-DH	23912852	Pass	PF-FKT-RM	2013-01-02 06:11	2013-01-02 06:11	REICHH	TM_PULSP	1 🐨	FP Defect Rate 32702 ppm	
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tput					0	32/15	84/15			40/15					<u>, m</u>	•		

The example shows a database with app. 3 million entries at a double-digit GB size.

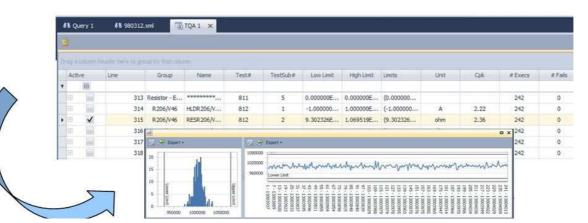
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• The **Browser** comprises **Statistics LITE**, i.e., in addition to the **reduFin** link there is a Cpk/Fail-Pareto, plus graphical representations and optional PDF-Reporting directly in the **Browser**:

	4	×										
	•		Id	Prod. Group	Product	Serial Number	Status	Test System	Start Time	Stop Time	Operator	TProgra
980312_980313			7							A 1000000000000		
	•		60537	EGO	980312_98	13003937	Pass	31	2013-01-10 07:43	2013-01-10 07:44	FERTIGUNG	75.4
	-		60538	EGO	980312_98	13003838	Pass	31	2013-01-10 07:46	2013-01-10 07:47	FERTIGUNG	75.4€
			60539	EGO	980312_98	13003918	Pass	31	2013-01-10 07:47	2013-01-10 07:47	FERTIGUNG	75.4€
Today	2013-01-10 07:00 +		60540	EGO	980312_98	13003915	Pass	31	2013-01-10 07:47	2013-01-10 07:48	FERTIGUNG	75.4
	2015-10-01 22:15 🔻		60541	EGO	980312_98	13003888	Pass	31	2013-01-10 07:48	2013-01-10 07:49	FERTIGUNG	75.4
31/20			60542	EGO	980312_98	13003917	Pass	31	2013-01-10 07:49	2013-01-10 07:49	FERTIGUNG	75.4 (
01120			60543	EGO	980312_98	13003889	Pass	31	2013-01-10 07:50	2013-01-10 07:50	FERTIGUNG	75.46
			60544	EGO	980312_98	13003890	Pass	31	2013-01-10 07:51	2013-01-10 07:51	FERTIGUNG	75.46
			60545	EGO	980312_98	13003887	Pass	31	2013-01-10 07:51	2013-01-10 07:52	FERTIGUNG	75.4 (
	•		60546	EGO	980312_98	13003893	Pass	31	2013-01-10 07:52	2013-01-10 07:53	FERTIGUNG	75.4 €
			60547	FGO	980312 98	13003894	Pass	31	2013-01-10 07:53	2013-01-10 07:53	FERTIGUNG	75 44





• Further PCB and test analyses:

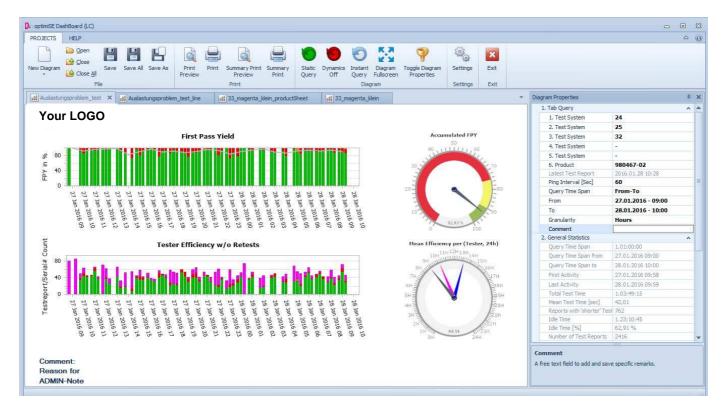
	Product Name	TProgram	Test System	PCB's	First Pass Y	Yield	Pa	ss PCB's	Fail/Interr	u Reb	est(s)	1st Retest	2nd R		
	980381	75,469,132	5	15	93.33	93.33		14		1	0	(
	980381	75.469.132	4	15	100.00	100.00		15		0	0	()		
	980381	75.492.804	3	1053	99.72	99.72		1050		3	3	3	0		
	980381	75.469.857	3	300	Test Details	Test Details									
	980.381	75.469.671	3	576	8	b									
144	+ + Record	1 of 337 🕨	PF PFI 4		Line	Group	Name	Test#	TestSub#	Status	Result	Low Limit	High Limit	Rule	
all	Performance	Quality Re	eporting	est Details	P										
-					• 1	Nestabfrage	LNKNestab	448	1	Pass	1.337	0.	10.	ANL	
					2	SHO NET G	SHO NET G	149	1	Pass	20.62	10.	100.	ANL	
					3	E500	LNKE500 6	151	1	Pass	0.6	0.	10.	ANL	
					4	F501 d 1 of 293	INKE501.6	153	1	Pace	0 837	n	10	ΔNI	
					III II I Recon	_		Test Details					_		h
e					Con Decementation	The providence of the	Charles III								
ort 🕶	Hour Day Week M	Ionth Year													
_						- 100%		1							
-							Pass Fail								
					_	60%	Interrupte	3							
-							FPY								
						- 40% LE	-	-1							
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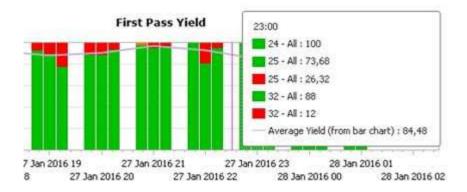
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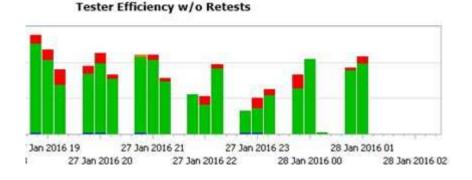


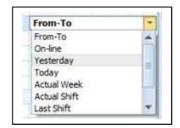
Das Tester DashBoard

Various granularities in time, views and fixed, resp. moving time intervals to display in great detail FPY and Tester Efficiency on **independent** work sheets.





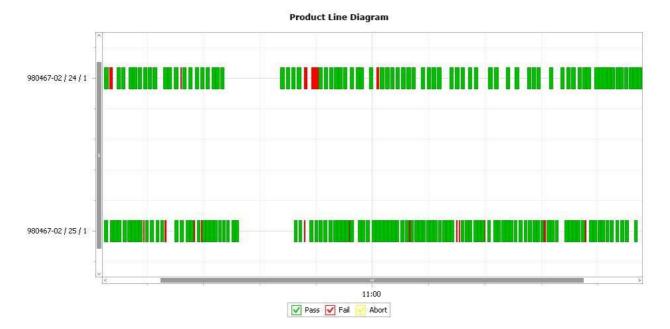




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The ,Product Line Sheet' displays the actual sequence of PCB passing through the tester(s) with the thickness of the bars corresponding to the individual test times:



Detailed statistics describes the devices under test:

2. General Statistics	^	Mean Efficiency per (Tester, 2-
Query Time Span	09:00:00	10H 11H 12H 13H
Query Time Span from	27.01.2016 17:00	9H 10H 10H 14H
Query Time Span to	28.01.2016 02:00	BH JUNE 16
First Activity	27.01.2016 16:59	78.
Last Activity	28.01.2016 01:58	
Total Test Time	10:51:54	611 3
Mean Test Time [sec]	42,38	5H =
Reports with 'shorter' Test	113	
Idle Time	16:08:06	48
Idle Time [%]	59,76 %	3H
Number of Test Reports	937	
Number of Devices under	833	
3. Tester-Individual	^	1H 03.37 023H
First Pass Yield per Tester	90,27%, 92,72%, 92,69%,	0H 24H
Serial # with First Pass	269, 293, 203, 0, 0	
Serial# with 'Last Pass'	295, 313, 213, 0, 0	
Serial# with only 'Pass'	269, 293, 203, 0, 0	
Serial# with only 'Fail/Abo	3, 3, 6, 0, 0	Include Week-ends? False
Serial # with ReTests	30, 25, 14, 0, 0	Display Handling-Times? True
4. Tester-Combined	^	The stand of the s
Accumulated FPY	91,84%	Display Handling-Times?
'Pass' Serial# over all Test	765	Handling Times are calculated and displayed:
'Fail/Abort' Serial# over all	12	Magenta Arrow = Test time plus actual handling time.
Retest Serial# over all Tes	69	Blue Arrow = Test time plus planned handling time.
5. Selected Component	~	135
Include Week-ends?	False	
	525.000000	

Actual (Test Times + planding Times)
 Actual (Test Times + planding Times)
 HandlingTimes)
 are displayed!

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Need more information? Please see www.optimise.de

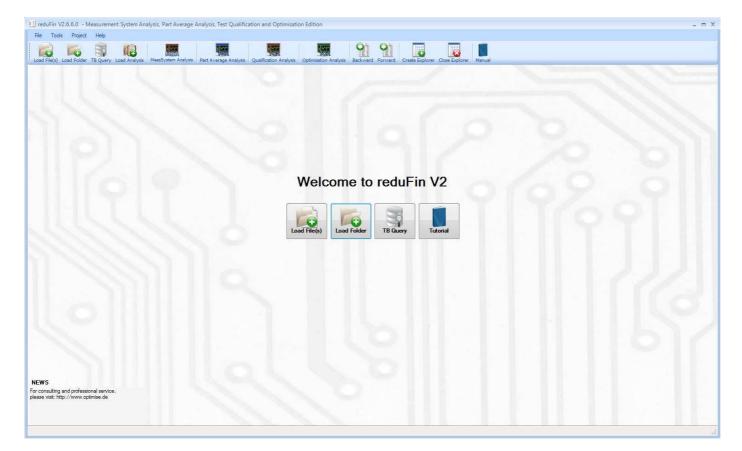
• •



The reduFin Suite™ -

Best suited for GR&R, Part Average Analysis, Qualification and Optimisation of testing of mounted printed circuit boards

reduFin offers four, mutually *independent* modules:



Measurement System Analysis

- Repeatability
- Reproducibility
- Detailed Reporting
- for all tests with a few clicks

Test Qualification

- Properties of single tests
 - Cpk simulations
- Comparison between sockets, testers, lots
 - Graphical representation of tests

Part Average Analysis

- Local quality outliers
 - Floating Cpk's

Test Optimisation

- Test correlations, escape risks
- Information content of tests
 - Test coverage overlap
- Test time overhead due to redundancy

Test logs can be loaded directly for any data formats or forwarded into **reduFin** from the **TestBase.**

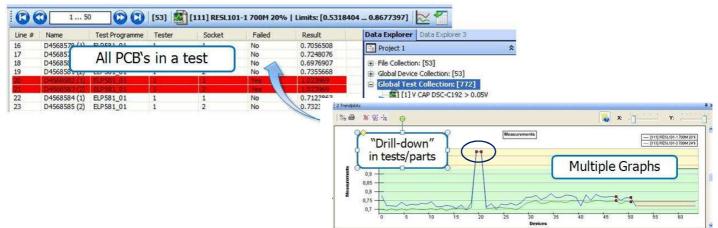
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Monitoring

• Details about parts and tests are only a few clicks away in the **Data Explorer**

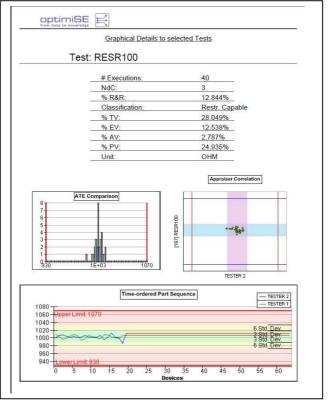
Project 1		1568615 (2) [642] 🛛 🏹	File: D45686	o15.txt				
- File Collection: [53]	Line #	Name	Number	Subnumber	Failed	Result	Low Limit	High Limit
The second s	348	HLDC251 10NF +10% -10%	418	1	No	1.1E-06	0	4E-05
E SFile: C:\Dokumente und Einstellungen'	349	CAPC251 10NF +10% -10%	418	2	No	1.06E-08	7.5E-09	1.25E-08
Device Collection:	350	HLDC320 100NF +10% -10%	419	1	No	2.7E-06	0	5.4E-05
Test Collection:	351	CAPC320 108/4 + 10% - 10%	419	2	Yes.	1176E-07	8.18-46	117E-07
File Information	352	HLDC323 100NF +10% -10%				-06	0	5.4E-05
File: C:\Dokumente und Einstellungen	353	CAPC323 100NF +10% -10%	Δ	ll tests of	> DCB	95E-07	8.3E-08	1.2E-07
	354	HLDC327 100NF +10% -10%		11 16313 01	arco	-06	0	5.4E-05
🗄 🚱 File: C:\Dokumente und Einstellungen'	355	CAPC327 100NF +10% -10%	421	2	INU	1.1245E-07	8.3E-08	1.2E-07



GR&R

• A GR&R Analysis with comprehensive reporting for all tests in the test programme at a few clicks

	e of Analysis
MS.	А Туре 1
0	MSA Type 1 Repeatability, M parts measured N times.
MS.	A Type 2
	uge Repeatability and Reproducibility, ng Equipment, Appraiser and Part Variation
O	Operator Distinction from File Operator IDs can be found in Log-Files
0	No a priori Operator Distinction -> Customer specific Solution
MS.	A Type 3
0	MSA Type 3 (for ATE) Gauge Repeatability and Reproducibility using only Equipment and Part Variation
	OK Cancel



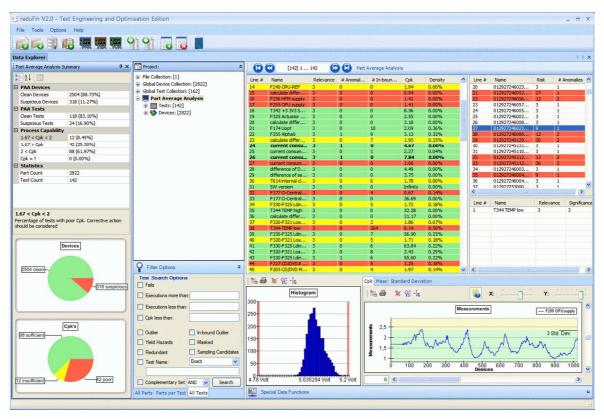
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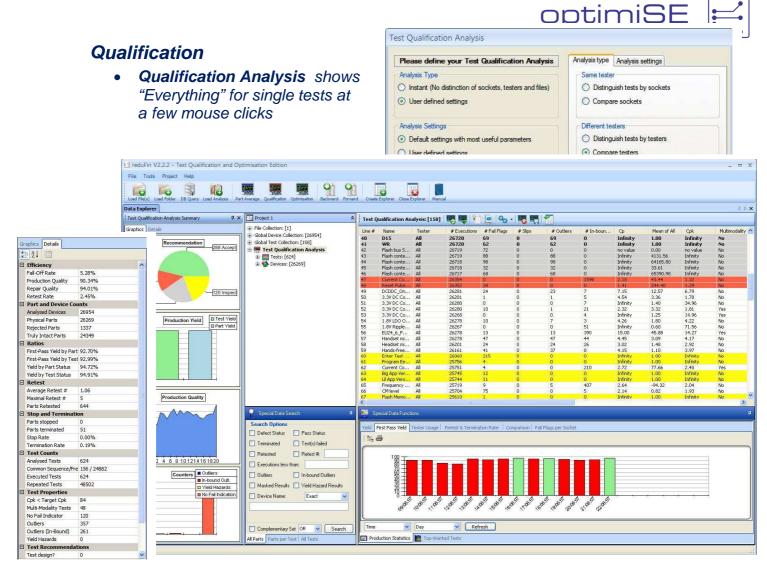
Load File(s) Load Folder TB Query Load Analysis Meas	System Analysis Part Average Analysis Qualifica	IFE/A tion Analysis C	TOR Iptimisation Analysis	Backward	Forward Create E	xplorer Close E	cpiorer Manual						
Data Explorer	Dec. 2						one kanti						
MSA Type 1 Summary 🛛 🗛 🗙	🔁 Analysis Project	* Meas	urement Syster	n Analysis Ty	/pe 1: [146] 🛛 🜉	1 141	5 1						
21 1	- File Collection: [1]	Line #	Name	Socket	# Executions	Classificati	Repeatability	Cq	Gauss Outs	Bias	Nominal V	Biased Rep	Cgk
Exercise Ensemble	Global Device Collection: [50]	10	A-CAP:C253	All	50			4,748	0.00 %	3.136e-011	1.000e-009	18.789%	
Analysed Devices 50	Global Test Collection: [146]	10	A-CAP:C233 A-CAP:C13	All	50	Acceptable Acceptable	4.212 % 0.843 %	23.719	0.00 %	8.642e-010	2.200e-008	-13.680%	1.064
Analysed Tests 146	😑 🎫 MSA Type 1	12	A-CAP:CIS A-CAP:C20	All	50	Acceptable	0.146 %	136.837	0.00 %	-1.288e-004	8.803e-008	-0.065%	-308.063
Repeatability Parameters	👜 - 🧱 Tests: [146]	13	A-CAP:C20 A-CAP:C403	All	50	Acceptable	0.140 %	46.536	0.00 %	-2.730e-009	6.800e-008	-0.065%	-308.005
Gaussian Outsider 0.27 %	🖽 😭 Devices: [50]	14	A-CAP:C403	All	50	Acceptable	0.416 %	48.026	2,00 %	-3.457e-009	6.800e-008	-0.731%	-27.341
RI Multiplier 6	and a state of the state of	14	A-CAP:C404	All	50	Acceptable	0.199 %	100.522	0.00 %	3.515e-009	2.200e-007	0.411%	48,710
Significance Level 5.00 %		16	A-CAP:C24	All	50	Acceptable	0.199 %	51,795	0.00 %	-1.687e-010	2.200e-007 2.200e-009	-0.265%	-75.473
Tolerance Fraction 20.00 %		17	A-CAP:C35	All	50	Acceptable	0.482 %	41.495	2.00 %	-2.949e-010	1.000e-008	8.315%	2.405
Repeatability Test Statistics		18	A-CAP:C400	All	50	Acceptable	0.665 %	30.080	0.00 %	-4.532e-010	1.000e-008	-1.649%	-12.130
Acceptable 97.26% (142) / < 15%		19	A-CAP:C48	All	50	Insufficient	27.184 %	0.736	6.00 %	1.629e-011	1.000e-010	-20,489%	-0.976
Marginal 0.68% (1) / <= 20%		20	A-CAP:C250	All	50	Acceptable	7.207 %	2.775	0.00 %	-4.100e-012	1.000e-010	-25.627%	-0.780
Unsufficient 2.05% (3) / > 20%		1 21	A-CAP:C252	All	50	Acceptable	0.472 %	42.412	2.00 %	-3.858e-012	1.000e-010	-2.292%	-8.727
Unversioned 0.00% (0) / R = NaN		22	A-CAP:C255	All	50	Acceptable	0.290 %	68.865	0.00 %	-2.420e-006	3.610e-005	-0.272%	-73.643
Test Comparison w.r.t. Gaussian Outsider		23	A-CAP:C350	All	50	Acceptable	0.470 %	42.546	0.00 %	-3.761e-007	4.700e-006	-0.297%	-67.288
Less Outsider 87.67% (128) / <- 0.27 %		24	A-CAP:C354	All	50	Acceptable	0.325 %	61.593	0.00 %	-3.846e-007	4.700e-006	-0.198%	-100.977
More Outsider 12.33% (18) / > 0.27 %		25	A-CAP:C355	All	50	Acceptable	0.275 %	72,732	0.00 %	-3.232e-007	4.700e-006	-0.226%	-88,596
Zero-Hypothesis for Bias		26	A-CAP:C356	All	50	Acceptable	0.429 %	46.669	0.00 %	-3.490e-007	4.700e-006	-0.307%	-65.112
Accepted 0.00% (0) / with 5.00 %		17 27	A-CAP:C750	All	50	Marginal	15.810 %	1.265	4.00 %	9.254e-006	7.500e-005	-9.076%	-2.204
Rejected 78.77% (115) / with 5.00		28	A-CAP:C32	All	50	Acceptable	2.929 %	6.829	0.00 %	-1.095e-010	2.000e-009	-13.545%	-1.477
Acceptable		29	A-CAP:C33	All	50	Acceptable	14,292 %	1,399	0.00 %	-5.402e-011	1.000e-009	-26.300%	-0.760
Portion of tests with acceptable Repeatability. No		30	A-CAP:C40	All	50	Acceptable	1.547 %	12.928	0.00 %	-6.584e-011	2.000e-009	-28.054%	-0.713
corrective action is needed.		31	A-CAP:C360	All	50	Acceptable	0.533 %	37.558	0.00 %	-3.584e-011	1.000e-009	-3.671%	-5.449
		I 32	A-CAP:C752	All	50	Acceptable	7.747 %	2.582	0.00 %	-9.159e-011	1.000e-009	-6.419%	-3.116
Repeatability Distribution		33	A-CAP:C759	All	50	Acceptable	10.913 %	1.833	0.00 %	4,432e-011	1.000e-009	-22,863%	-0.875
		1 34	A-CAP:C452	All	50	Acceptable	1.584 %	12.630	0.00 %	-5.992e-010	4.700e-009	-0.688%	-29.071
		1 35	A-CAP:C357	All	50	Acceptable	0.438 %	45.610	0.00 %	-3.427e-007	4.700e-006	-0.324%	-61.673
142 acceptable		36	A-CAP:C358	All	50	Acceptable	0.446 %	44.812	0.00 %	-3.810e-007	4.700e-006	-0.276%	-72.374
		1 37	A-CAP:C359	All	50	Acceptable	0.479 %	41.711	0.00 %	-3.767e-007	4.700e-006	-0.302%	-66.131
		38	A-CAP:C453	All	50	Insufficient	37.324 %	0.536	0.00 %	1.678e-011	9.000e-011	-19.975%	-1.001
		39	A-CAP:C454	All	50	Insufficient	36.415 %	0.549	0.00 %	-1.867e-012	1.000e-010	48.482%	0.413
Zero-Hypothesis Distribution		10	A-DIO:V10	All	50	Acceptable	0.152 %	131.828	0.00 %	No Referen	No Referen	No Referen	No Refere
115 rejected		1 41	A-DIO:V25	All	50	Acceptable	0.054 %	369.949	0.00 %	No Referen	No Referen	No Referen	No Refere
		1 42	A-DIO:V25	All	50	Acceptable	0.073 %	275.811	0.00 %	No Referen	No Referen	No Referen	No Refere
-0 accepted -31 unconclusive		43	A-DIO:V25	All	50	Acceptable	0.068 %	292.577	0.00 %	No Referen	No Referen	No Referen	No Refere
	O Special Data Filter	1051.6	pecial Data Functi				()						

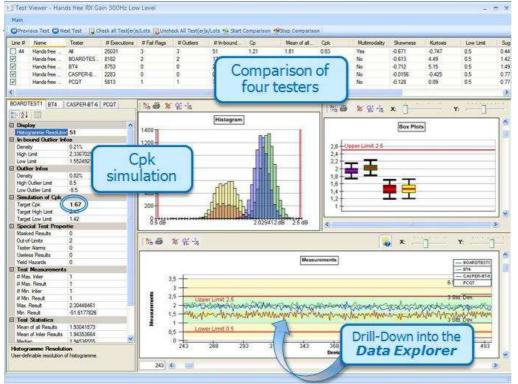
Part Average Analysis

A statistical method for latent defect diagnosis and avoidance



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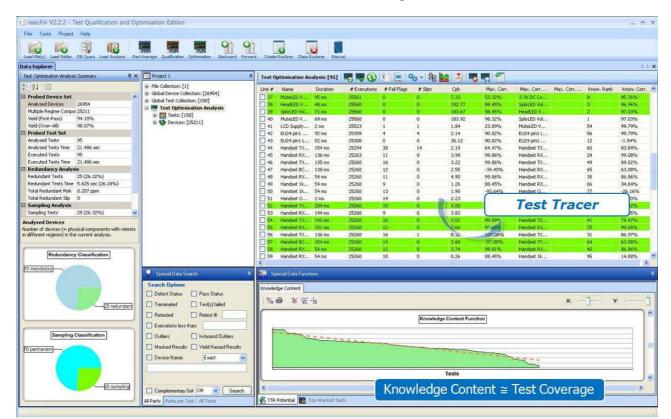
The **Test Viewer** provides a complete view on every test

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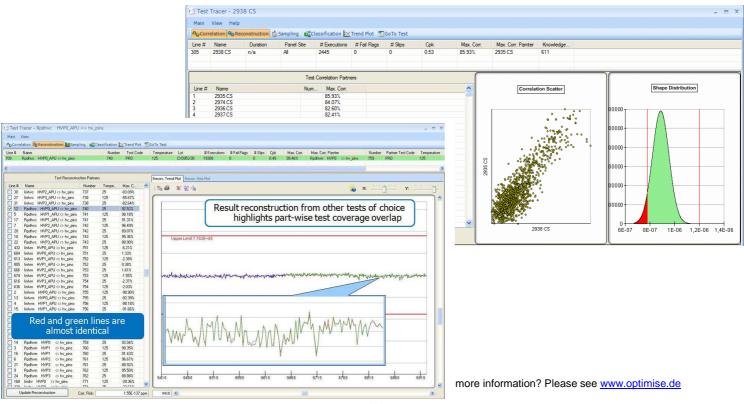


Optimisation

Optimisation depicts the interactions between tests. It goes way beyond any standard analysis software and determines knowledge content for every test. That reflects the test's contribution to the total test coverage.



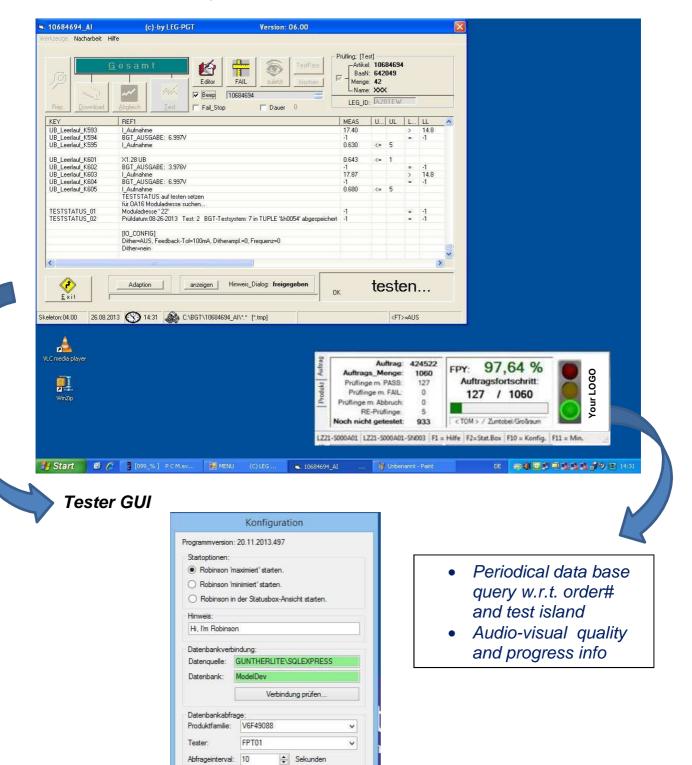
Optimisation estimates the risk of leaving out tests, so the expert can decide not to sample tests with reasonable probability of detecting defective parts.





Customised Tools – Two Examples

• Automated testing activity and quality control w.r.t. to order volume for manual assembly on test islands





The Test Floor Monitor

Tester- or server based, the **WatchDog** automatically monitors the correct execution of test programmes and logs parameters for production control. Deviations are reported into a data base.

Event Status of WatchDog WatchDog [1]:		
SUMMA		
Total devices processed:	58	
Devices differing from the golden samples		
DEVICES differing from one gorden samples		
Devices missing a golden sample reference		
Devices having tests missing:	0 (0.0%) 15 (25.9%)	
Devices having tests with changed limits:	0 (0.0%)	
dog Devices having unreferenced tests:	11 (19.0%)	
Total missing tests:	88	
Total missing tests:	88	
Total missing tests: Total tests with changed limits: Total unreferenced tests:	88 0	
Total missing tests: Total tests with changed limits: Total unreferenced tests:	88 0	
Total missing tests: Total tests with changed limits: Total unreferenced tests: Operating Status of WatchDog	88 0	
Total missing tests: Total tests with changed limits: Total unreferenced tests: Operating Status of WatchDog	88 0	
Total missing tests: Total tests with changed limits: Total unreferenced tests: Operating Status of WatchDog	88 0	
Total missing tests: Total tests with changed limits: Total unreferenced tests: Operating Status of WatchDog	88 0	
Total missing tests: Total tests with changed limits: Total unreferenced tests: Operating Status of WatchDog	88 0	
Total missing tests: Total tests with changed limits: Total unreferenced tests: Operating Status of WatchDog	88 0	

The **EventViewer** evaluates and administrates event patterns (and will be extended by production control parameters and statistics).

	ntViewer - opti	miSit Gmbli					
Main	Setup Help						
	Lingin 🎇 Logo	iff 🔍 Event	Query 🔀 Auto Ever	t Query 🐇 Quick Launch 🥈	Show Profiles		
		()			- ur.		
N	4 4 of 9		3.0				
	Event Pattern	Frequency	Position	Name	Limits	Original Limits	Events
	1	87	► 1	measure 3.3Vdc at T0	19 Limits (3.2:3.4)	Briginal Limits [Unkno	Eventa
	2	1	2	Measure voltage at T0	Limits (0.1:0.15)	Original Limits (0:0.15)	
	3	1	3	Measure voltage at T0	Limits [0.1:0.15]	Original Limits [Unkno	8
e î	4	1	4	meaaaasure 3.3Vdc at	Limits [3.2:3.4]	Original Limits [Unkno	
	5	1	94 - 3 <u>6</u>				0
	6	1					
	7	1					6 2
	8	1					
	9	1					
							Program Changed Missing Test Additional Test
							Unreferenced Test Limits Changed Ok
-							
	Time Stamp	Tester ALTWF026			ing Test Limits C		Device Properties
	2/23/2006 10:26	ALTWF026	No	No Yes	Yes	Yes	ID: 3060800220
							Product: B&D A13 Power:V1.0
		Pattern				×	Program: C:\FTS\Apps\B&O_A13\V1.0\sequences\B&O_A13_Power.se
		- «Devic	A2			·	Tester: ALTWF026
		 d>	3060800220				Socket 0
			duct>B&O A13 Power:				Status: Passed
			stplan>C:\FTS\Apps\B sequences\B&O A13	&O_A13\V1.0 Power.seq:C:\FTS\Apps\B&O_/	413\V1.0		Time Stamp: 2/23/2006 10:26:27 AM
		10	Config\B&OA13_Powe	.ini			Comments
			ster>ALTWF026cket>0	r>			sdsd
			atus>True				3434
				10:26:27.0000000			Complete
			singTest> 'est Name='measure 3.	3Vdc at T019' LowLimit='3.2' High	hl imit="3.4"	5	Save
		(OrigLowLimit="NaN" Orig	HighLimit="NaN" Version="0" />		1	
			issingTest>				
			itsChanged> 'est Name= 'Measure vo	Itage at T014' LowLimit='0.1' Hig	hLimit="0,15"		
		(OrigLowLimit="0" OrigHig	hLimit="0.15" Version='1" />			
			mitsChanged> ditionalTest>				
				ltage at T014' LowLimit="0.1' Hig	hLimit="0.15"		
		(OrigLowLimit="NaN" Orig	HighLimit="NaN" Version="1" />			
				e 3.3Vdc at T019" LowLimit="3.2"			
		1					
			HighLimit=" 3.4" OrigLowL IditionalTest>	.imit="NaN" OrigHighLimit="NaN" Ve	ersion="0" />		

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